Amorphous (Zr,Hf)$_{37}$Si$_{63}$ alloys were produced by sputtering. Their total structure factors were determined by X-ray diffraction. Using the methods of isomorphous substitution and Reverse Monte Carlo simulation, the partial pair correlation functions were obtained. The results were compared with the partial functions of amorphous Ti$_{60}$Si$_{60}$. In the amorphous alloys under investigation the transition metal – metalloid correlation dominates the short range order.

**Key words:** Amorphous Zr-Hf-Si; X-ray Diffraction; RMC Model.